



520.41064X00/NT0550US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Akira HAMAMATSU *et al.*
Application No.: 10/050,776
Filed: 18 January 2002
For: APPARATUS AND METHOD FOR INSPECTING DEFECTS
Art Unit: 2877
Examiner: M.P. Stafira
Conf. No: 9567

REQUEST FOR CONSIDERATION OF PREVIOUSLY-SUBMITTED REFERENCES

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-14501

18 July 2005

Sir:

In the matter of the above-identified application, Applicant had previously submitted four (4) foreign references together with the original filing of the application, and the Examiner has yet to acknowledge consideration of such references. For the Examiner's convenience and initialing, provided herewith is a PTO/SB/08A form (replacing the originally-filed non-USPTO-form) for listing such references. For the Examiner's further convenience, also provided herewith is a redundant copy of such four (4) foreign references. Applicant respectfully petitions the Commissioner for an extension for time (to whatever extent necessary), and authorization is herein give to charge any fee deficiency whatsoever to ATSK Deposit Account No. 01-2135.

Respectfully submitted,

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